

Data sheet acquired from Harris Semiconductor SCHS033

BCD-to-Decimal Decoder

High-Voltage Types (20-Volt Rating)

cD4028B types are BCD-to-decimal or binary-to-octal decoders consisting of buffering on all 4 inputs, decoding-logic gates, and 10 output buffers. A BCD code applied to the four inputs, A to D, results in a high level at the selected one of 10 decimal decoded outputs. Similarly, a 3-bit binary code applied to inputs A through C is decoded in octal code at output 0 to 7 if D = "0". High drive capability is provided at all outputs to enhance dc and dynamic performance in high fan-out applications.

The CD4028B-Series types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

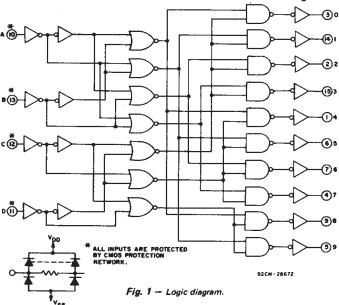
CD4028B Types

Features:

- BCD-to-decimal decoding or binary-to-octal decoding
- High decoded output drive capability
- "Positive logic" inputs and outputs. . . .
 - decoded outputs go high on selection
- Medium-speed operation...
 - t_{PHL} , t_{PLH} = 80 ns (typ.) @ V_{DD} = 10 V
- Standardized, symmetrical output characteristics
 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V over full package-temperature range;
 100 nA at 18 V and 25°C
- Noise margin (over full packagetemperature range):
 - 1 V at V_{DD} = 5 V
 - 2 V at V_{DD} = 10 V
 - 2.5 V at V_{DD} = 15 V
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 138, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

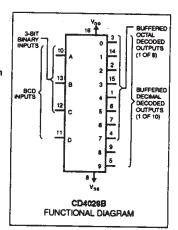
- Code conversion Indicator-tube decoder
- Address decoding—memory selection control

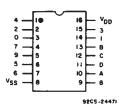


MAXIMUM RATINGS, Absolute-Maximum Values:

LEAD TEMPERATURE (DURING SOLDERING):

DC SUPPLY-VOLTAGE RANGE, (VDD)	
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	0.5V to V _{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55°C to +100°C	500mW
For T _A = +100°C to +125°C	Derate Linearity at 12mW/OC to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package	ge Types)
OPERATING-TEMPERATURE RANGE (TA)	55°C to +125°C
STORAGE TEMPERATURE RANGE (Tstg)	65°C to +150°C





Top View
TERMINAL DIAGRAM

TABLE I - TRUTH TABLE

D	С	В	Α	0	1	2	3	4	5	6	7	8	9
0	0	0	0	1	0	0	0	0	0	0	0	0	0
0	0	0	1	0	1	0	0	0	0	0	0	0	0
0	0	1	0	0	0	1	0	0	0	0	0	0	0
0	0	1	1	0	0	0	1	0	0	0	0	0	0
0	1	0	0	0	0	0	0	1	0	0	0	0	0
0	1	0	1	0	0	0	0	0	1	0	0	0	0
e	1	1	0	0	0	0	0	0	0	1	0	0	0
0	1	1	1	0	0	0	0	0	0	0	1	0	0
1	0	0	0	0	0	0	0	0	0	0	0	1	0
1	0	0	1	0	0	0	0	0	0	0	0	0	1
1	0	1	0	0	0	0	0	0	0	0	0	0	0
1	0	1	1	0	0	0	0	0	0	0	0	0	0
1	1	0	0	0	0	0	0	0	0	0	0	0	0
1	1	0	1	0	0	0	0	0	0	0	0	0	0
1	1	1	0	0	0	0	0	0	0	0	0	0	0
1	1	1	1	0	0	0	0	0	0	0	0	0	0

I = HIGH LEVEL

0 = LOW LEVEL

CD4028B Types

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LI	MITS	UNITS
	MIN.	MAX.	
Supply Voltage Range (For T _A = Full Package			
Temperature Range)	- 3	18	V

STATIC ELECTRICAL CHARACTERISTICS

CHARACTER-	CON	OITIO	vs [?]	LIMITS AT INDICATED TEMPERATURES (°C)											
ISTIC	Vo	VIN	VDD						+25		UNITS				
	(v)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.					
Quiescent Device	-	0,5	5	5	5	150	150	- :	0.04	5					
Current,	-	0,10	10	10	10	300	300	-	0.04	10					
IDD Max.	_	0,15	15	20	20	600	600	-	0.04	20	μA				
	_	0,20	20	100	100	3000	3000	-	0.08	100	1				
Output Low	0.4	0,5	5	0.64	0.61	0,42	0,36	0.51	1	-					
(Sink) Current	0,5	0,10	10	1.6	1.5	1,1	0.9	1.3	2.6		1				
IOL Min.	1,5	0,15	15	4.2	4	2.8	2.4	34	6.8	-	1				
Output High	4.6	0,5	5	-0.64	-0,61	-0.42	-0.36	-0.51	1	-	mA				
(Source) Current, IOH Min.	2.5	0,5	• 5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	!				
	9.5	0,10	10	-1.6	-1,5	-1.1	-0.9	-1.3	-2.6	-	Í				
	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	- 6.8	-					
Output Voltage:	-	0,5	5		0	.05		_	0	0.05					
Low-Level, VOL Max.	_	0,10	10		0	.05		-	0	0.05	v				
	_	0,15	15		0	.05		-	0	0.05					
Output Voltage:	-	0,5	5		4.	.95		4.95	5	-					
High Level	-	0,10	10		9.	.95		9.95	10	-					
VOH Min.	_	0,15	15		14	.95		14.95	15	-					
Input Low	0.5, 4.5	-	5		1	.5		_	-	1.5					
Voltage,	1, 9	_	10			3		_	-	3					
V _{IL} Max.	1.5,13.5	_	15			4		-	-	4					
Input High	0.5, 4,5		5		3	.5		3,5	_	_	V				
Voltage,	1, 9		10			7		7	_						
VIH Min.	1.5,13.5	-	15		1	1		11	_	-					
Input Current I _{IN} Max.	-	0,18	18	±0,1	±0.1	±1	±1	-	±10−5	±0.1	μΑ				

DYNAMIC ELECTRICAL CHARACTERISTICS at T $_A$ = 25°C, C $_L$ = 50 pF, Input t_r,t_f = 20 ns, R $_L$ = 200 $\rm k\Omega$

CHARACTERISTIC	TEST CONDITIONS	LIM		
	V _{DD} (V)	Тур.	Max.	UNITS
Propagation Delay Time:	5	175	350	ns
^t PHL ^{, t} PLH	10	80	160	
	15	60	120	
	5	100	200	
Transition Time	10	50	100	ns
tTHL, tTLH	15	40	80	
Input Capacitance, C _{IN}	_	5	7.5	pF

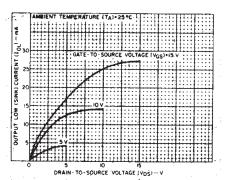


Fig. 2 — Typical output low (sink) current characteristics.

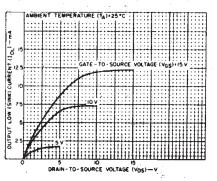


Fig. 3 — Minimum output low (sink) current characteristics.

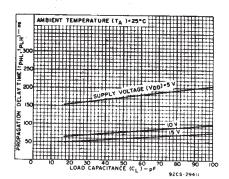


Fig. 4 — Typical propagation delay time as a function of load capacitance.

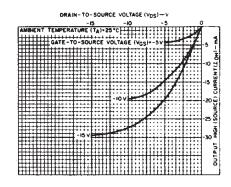


Fig. 5 — Typical output high (source) current characteristics.

TABLE II - CODE CONVERSION CHART

		INPUT CODES																				
	Hexa - Decimal Decimal																					
INPUTS	Z EN AT								1	ou	TP	UT	NI	JM	8 E	R						
DCBA	48 85	4 R	Ä	25	₹	4.2	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
0000	0	0			0	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
0001	1	1			1	1	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0
0 0 1 0	2	3		0	2	2	0	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0
0 0 1 1	3	2	0	3	3		0	0	0	1	0	0	0	0	0	0	0	0	0	0	0	0
0 1 0 0	4	7	1	4	4		0	0	0	0	1	0	0	0	0	0	0	0	0	0	0	0
0 1 0 1	5	6	2		Ц	3	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	0
0 1 1 0	6	4	3	1		4	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0
0 1 1 1	7	5	4	2	Ц		0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0
1000	8	15	5				0	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0
1001	9	14	6			5	0	0	0	0	0	0	0	0	0	1	0	0	0	0	0	0
1010	10	12	7	9		6	0	0	0	0	0	0	0	0	0	0	1	0	0	0	0	0
1011	11	13	8		5		0	0	0	0	0	0	0	0	0	0	0	1	0	0	0	0
1 1 0 0	12	8	9	5	6		0	0	0	0	0	0	0	0	0	0	0	0	1	0	0	0
1 1 0 1	13	9	$oxed{oxed}$	6	7	7	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0	0
1 1 1 0	14	11		8	8	8	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0
1 1 1 1	15	10		7	9	9	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1

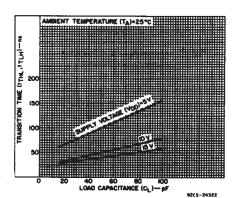


Fig. 8 — Typical transition time as a function of load capacitance.

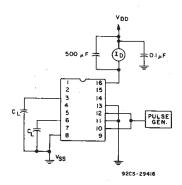


Fig. 10 — Dynamic power dissipation test circuit.

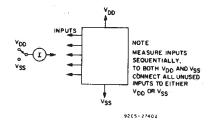


Fig. 9 - Input current test circuit.

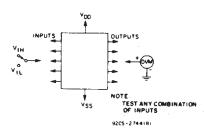


Fig. 11 - Input voltage test circuit.

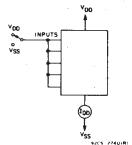


Fig. 12 — Quiescent device current test circuit.

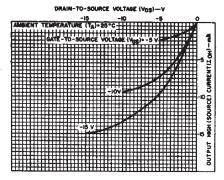


Fig. 6 — Minimum output high (source)

current characteristics.

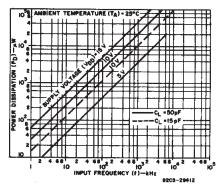


Fig. 7 — Typical dynamic power dissipation as a function of input frequency.

TYPICAL APPLICATIONS

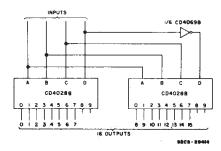
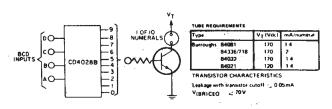


Fig. 13 — Code conversion circuit.

The circuit shown in Fig.13 converts any 4-bit code to a decimal or hexadecimal code. Table 2 shows a number of codes and the decimal or hexadecimal number in these codes which must be applied to the input terminals of the CD4028B to select a particular output. For example: in order to get a high on output No. 8 the input must be either an 8 expressed in 4-Bit Binary code, a 15 expressed in 4-Bit Gray code, or a 5 expressed in Excess-3 code.

CD4028B Types



*(Trademark) Burroughs Corp.

Fig. 14 — Neon readout (Nixie Tube^{*}) display application.

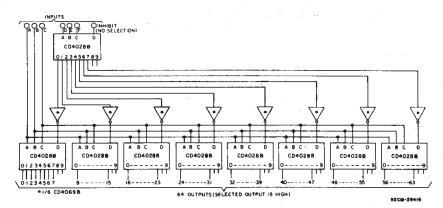
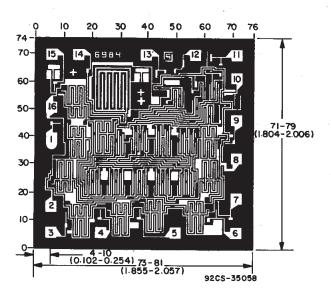


Fig. 15 - 6-bit binary to 1-of-64 address decoder.



CD4028BH DIMENSIONS AND PAD LAYOUT

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3}) inch).

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